

Supplementary Information

Incorporation of isophthalate ion derivatives into octacalcium phosphate for enhanced diagnostic bioimaging applications

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Characterisation

The elemental composition of the SuIP-OCP was determined by X-ray photoelectron spectroscopy (XPS, PHI 5000 Versa Probe III, Ulvac-Phi, Japan). The excitation source used was Al K α radiation at 50 W and 200 μ M. The vacuum degree at 1.7×10^{-6} Pa, and an Ar ion gun was employed during measurement. The pass energy was set to 224 eV and 27 eV for the wide scan and narrow scan, respectively. C1s is utilized as a reference peak for calibration.

XPS spectrum of SuIP-OCP

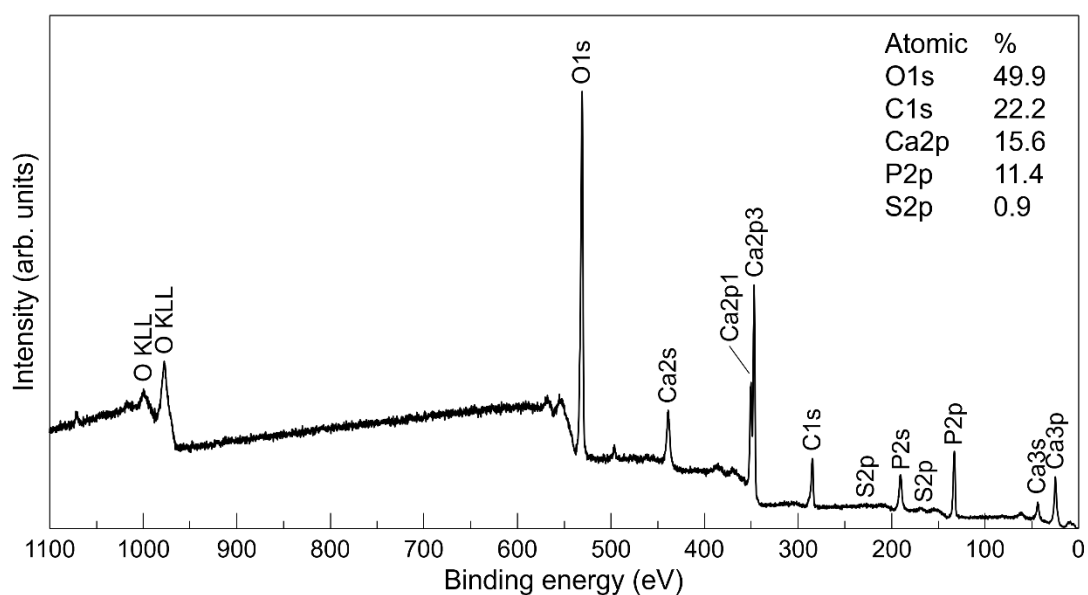


Figure S1. XPS spectrum of O1s, C1s, Ca2p, P2p, and S2p obtained from SuIP-OCP.